# MSKSEMI 美森科













ESD

TVS

TSS

MOV

GDT

PLED

**MMDT5451** 

## **Product specification**



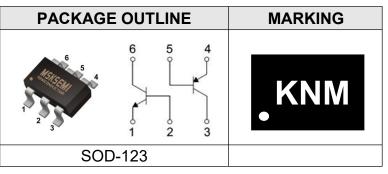




#### **FEATURES**

- Epitaxial Planar Die Construction
- Ideal for low Power Amplification and Switching
- One 5551(NPN), one 5401(PNP)

#### **Reference News**



#### MAXIMUM RATINGS (Ta=25°C unless otherwise noted)

Symbol	Parameter	Value	Units
Vсво	collector- Base Voltage	180	V
VCEO	collector-Emitter Voltage	160	V
VEBO	Emitter-Base Voltage	6	V
lc	collector current -continuous	0.2	А
Pc	collector Power Dissipation	0.2	W
R •JA	Thermal Resistance, Junction to Ambient		τ/w
TJ,Tstg	operation Junction and storage Temperature Range		τ

#### ELECTRICAL CHARACTERISTICS NPN 5551 (Ta=25°C unless otherwise specified)

Parameter	Symbol	Test conditions	Min	Тур	Мах	Unit
Collector-base breakdown Voltage	V <sub>(BR)cBO</sub>	Ic=100µA,IE=0	180			V
Collector-emitter breakdown Voltage	V <sub>(BR)cEO</sub>	$I_c=1 \text{ mA}, I_B=0$	160			V
Emitter-base breakdown Voltage	V <sub>(BR)EBO</sub>	l <sub>E</sub> =10μA, l <sub>c</sub> =0	6			V
Collector cut-off current	I <sub>cBO</sub>	V <sub>cB</sub> =120V, I <sub>E</sub> =0			0.05	μA
Emitter cut-off current	І <sub>ЕВО</sub>	V <sub>EB</sub> =4V, I <sub>c</sub> =0			0.05	μA
	h <sub>FE1</sub>	V <sub>cE</sub> =5V, I <sub>c</sub> =1mA	80			
DC current gain	h <sub>FE2</sub>	V <sub>cE</sub> =5V, I <sub>c</sub> =10mA	100		300	
	h <sub>FE3</sub>	V <sub>cE</sub> =5V, I <sub>c</sub> =50mA	30			
Collector emitter esturation Volters	V <sub>cE(sat)</sub>	Ic=10mA, IB=1mA			0.15	V
Collector-emitter saturation Voltage		I₀=50mA, I <sub>B</sub> =5mA			0.2	V
	V <sub>BE(sat)</sub>	I₀=10mA, I <sub>B</sub> =1mA			1	V
Base-emitter saturation Voltage		I₀=50mA, I <sub>B</sub> =5mA			1	V
Output Capacitance	Cobo	$V_{cB} = 10V, f = 1.0MHz, I_E = 0$			6.0	pF
Current Gain-Bandwidth Product	fT	$V_{cE}$ = 10V, I <sub>c</sub> = 10mA, f = 100MHz	100		300	MHz
Noise Figure	NF	$V_{cE}$ = 5.0V, I <sub>c</sub> = 200µA, R <sub>S</sub> = 1.0K Ω, f = 1.0KHz			8.0	dB



#### MAXIMuM RATINGS PNP 5401 (Ta=25 °C unless otherwise noted)

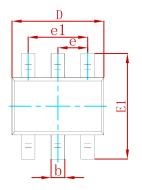
Symbol	Parameter	Value	units
V <sub>сво</sub>	collector- Base Voltage	-160	V
VCEO	collector-Emitter Voltage	-150	V
V <sub>EBO</sub>	Emitter-Base Voltage	-5	V
lc	collector current -continuous	-0.2	А
Pc	collector power DissiPation	0.2	W
R øja	Thermal Resistance, Junction to Ambient	625	τ/w
T <sub>J</sub> ,T <sub>stg</sub>	operation Junction and storage Temperature Range	-55~+150	т

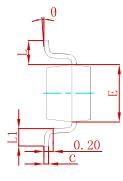
#### ELECTRICAL CHARACTERISTICS PNP 5401 (Ta=25<sup>T</sup> unless otherwise specified)

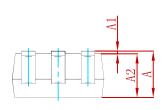
Parameter	Symbol	Test conditions	Min	Тур	Мах	unit
Collector-base breakdown Voltage	V <sub>(BR)cBO</sub>	l <sub>c</sub> =-100μA, l <sub>E</sub> =0	-160			V
Collector-emitter breakdown Voltage	V <sub>(BR)cEO</sub>	Ic=-1mA, IB=0	-150			V
Emitter-base breakdown Voltage	V <sub>(BR)EBO</sub>	l <sub>E</sub> =-10μA, l <sub>c</sub> =0	-5			V
Collector cut-off current	I <sub>cBO</sub>	V <sub>cB</sub> =-120V,I <sub>E</sub> =0			-50	nA
Emitter cut-off current	I <sub>EBO</sub>	V <sub>EB</sub> =-3V, I <sub>c</sub> =0			-50	nA
	h <sub>FE1</sub>	$V_{cE}$ =-5V, $I_c$ =-1mA	50			
DC current gain	h <sub>FE2</sub>	V <sub>cE</sub> =-5V, I <sub>c</sub> =-10mA	100		300	
	h <sub>FE3</sub>	V <sub>cE</sub> =-5V, I <sub>c</sub> =-50mA	50			
		Ic=-10mA, IB=-1mA			-0.2	V
Collector-emitter saturation Voltage	V <sub>cE(sat)</sub>	I <sub>c</sub> =-50mA, I <sub>B</sub> =-5mA			-0.5	V
		Ic=-10mA, I <sub>B</sub> =-1mA			-1	V
Base-emitter saturation Voltage	V <sub>BE(sat)</sub>	Ic=-50mA, I <sub>B</sub> =-5mA			-1	V
Output Capacitance	C <sub>obo</sub>	$V_{cB}$ =-10V, f = 1.0MHz, I <sub>E</sub> = 0			6.0	PF
Current Gain-Bandwidth Product	f⊤	$V_{cE}$ =-10V, I <sub>c</sub> =-10mA, f = 100MHz	100		300	MHz
Noise Figure	NF	$V_{cE}$ =-5.0V, I <sub>c</sub> =-200µA, R <sub>s</sub> = 10 Ω, f = 1.0KHz			8.0	dB



### PACKAGEMECHANICALDATA

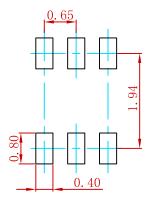






Symbol	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min	Max	Min	Max	
A	0.900	1.100	0.035	0.043	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.000	0.035	0.039	
b	0.150	0.350	0.006	0.014	
С	0.100	0.150	0.004	0.006	
D	2.000	2.200	0.079	0.087	
E	1.150	1.350	0.045	0.053	
E1	2.150	2.400	0.085	0.094	
е	0.650 TYP		0.026 TYP		
e1	1.200	1.400	0.047	0.055	
L	0.525 REF 0.021 REF		REF		
L1	0.260	0.460	0.010	0.018	
θ	0°	8°	0°	8°	

## Suggested Pad Layout



Note: 1.Controlling dimension:in millimeters. 2.General tolerance:±0.05mm. 3.The pad layout is for reference purposes only.

## **REEL SPECIFICATION**

P/N	PKG	QTY
MMDT5451	SOT-363	3000



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